

54AC11074, 74AC11074  
**DUAL D-TYPE POSITIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH CLEAR AND PRESET**

D2957, DECEMBER 1986 - REVISED APRIL 1993

- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Plastic Thin Shrink Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

### description

These devices contain two independent D-type positive-edge-triggered flip-flops. A low level at the Preset or Clear input sets or resets the outputs regardless of the levels of the other inputs. When Preset and Clear are inactive (high), data at the D input that meets the setup time requirements are transferred to the outputs on the low-to-high transition of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the D input may be changed without affecting the levels at the outputs.

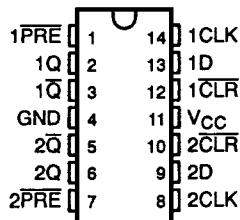
The 54AC11074 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11074 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

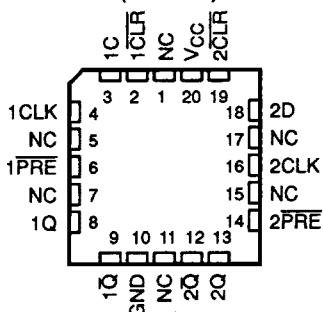
INPUTS				OUTPUTS	
PRE	CLR	CLK	D	Q	$\bar{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	$H^\dagger$	$H^\dagger$
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	$Q_0$	$\bar{Q}_0$

† This configuration is nonstable; that is, it will not persist when either Preset or Clear returns to its inactive (high) level.

**54AC11074 . . . J PACKAGE**  
**74AC11074 . . . D, N, OR PW PACKAGE**  
**(TOP VIEW)**



**54AC11074 . . . FK PACKAGE**  
**(TOP VIEW)**



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**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†**

Supply voltage range, $V_{CC}$ .....	-0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1) .....	-0.5 V to $V_{CC} + 0.5$ V
Output voltage range, $V_O$ (see Note 1) .....	-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) .....	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ) .....	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ ) .....	±50 mA
Continuous current through $V_{CC}$ or GND .....	±100 mA
Storage temperature range .....	-65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

**recommended operating conditions**

		54AC11074			74AC11074			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
$V_{CC}$	Supply voltage	3	5	5.5	3	5	5.5	V
$V_{IH}$	High-level input voltage	$V_{CC} = 3$ V	2.1		2.1			V
		$V_{CC} = 4.5$ V	3.15		3.15			
		$V_{CC} = 5.5$ V	3.85		3.85			
$V_{IL}$	Low-level input voltage	$V_{CC} = 3$ V		0.9		0.9		V
		$V_{CC} = 4.5$ V		1.35		1.35		
		$V_{CC} = 5.5$ V		1.65		1.65		
$V_I$	Input voltage	0	$V_{CC}$	0	$V_{CC}$	0	$V_{CC}$	V
$V_O$	Output voltage	0	$V_{CC}$	0	$V_{CC}$	0	$V_{CC}$	V
$I_{OH}$	High-level output current	$V_{CC} = 3$ V		-4		-4		mA
		$V_{CC} = 4.5$ V		-24		-24		
		$V_{CC} = 5.5$ V		-24		-24		
$I_{OL}$	Low-level output current	$V_{CC} = 3$ V		12		12		mA
		$V_{CC} = 4.5$ V		24		24		
		$V_{CC} = 5.5$ V		24		24		
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	0	10	0	10	ns/V
$T_A$	Operating free-air temperature	-55	125	-40	85	0	85	°C

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	T <sub>A</sub> = 25°C			54AC11074		74AC11074		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V <sub>OH</sub>	I <sub>OH</sub> = -50 µA	3 V	2.9			2.9		2.9		V
		4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
	I <sub>OH</sub> = -4 mA	3 V	2.58			2.4		2.48		
		4.5 V	3.94			3.7		3.8		
		5.5 V	4.94			4.7		4.8		
	I <sub>OH</sub> = -50 mA†	5.5 V				3.85				
	I <sub>OH</sub> = -75 mA†	5.5 V						3.85		
	I <sub>OL</sub> = 50 µA	3 V		0.1		0.1		0.1		
		4.5 V		0.1		0.1		0.1		
		5.5 V		0.1		0.1		0.1		
V <sub>OL</sub>	I <sub>OL</sub> = 12 mA	3 V		0.36		0.5		0.44		V
	I <sub>OL</sub> = 24 mA	4.5 V		0.36		0.5		0.44		
		5.5 V		0.36		0.5		0.44		
	I <sub>OL</sub> = 50 mA†	5.5 V				1.65				
	I <sub>OL</sub> = 75 mA†	5.5 V						1.65		
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V		±0.1		±1		±1		µA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	5.5 V		4		80		40		µA
C <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		3.5						pF

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements, V<sub>CC</sub> = 3.3 V ± 0.3 V (see Figure 1)

			T <sub>A</sub> = 25°C		54AC11074		74AC11074		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	Clock frequency		0	100	0	100	0	100	MHz
t <sub>w</sub>	Pulse duration	PRE or CLR low	4		4		4		ns
		CLK low or CLK high	5		5		5		
t <sub>su</sub>	Setup time, before CLK↑	Data high or low	5		5		5		ns
		PRE or CLR inactive	1		1		1		
t <sub>h</sub>	Hold time, after CLK↑		0		0		0		ns

timing requirements, V<sub>CC</sub> = 5 V ± 0.5 V (see Figure 1)

			T <sub>A</sub> = 25°C		54AC11074		74AC11074		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	Clock frequency		0	125	0	125	0	125	MHz
t <sub>w</sub>	Pulse duration	PRE or CLR low	4		4		4		ns
		CLK low or CLK high	4		4		4		
t <sub>su</sub>	Setup time, before CLK↑	Data high or low	3.5		3.5		3.5		ns
		PRE or CLR inactive	1		1		1		
t <sub>h</sub>	Hold time, after CLK↑		0		0		0		ns

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switching characteristics over recommended operating free-air temperature range,  
 $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TA = 25°C			54AC11074		74AC11074		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			100	125		100		100		
t <sub>PLH</sub>	PRE or CLR	Q or $\bar{Q}$	1.5	5.8	9.3	1.5	10.5	1.5	10	ns
t <sub>PHL</sub>			1.5	6.5	11.4	1.5	12.9	1.5	12.2	
t <sub>PLH</sub>	CLK	Q or $\bar{Q}$	1.5	7.7	10.5	1.5	12.1	1.5	11.3	ns
t <sub>PHL</sub>			1.5	7.3	9.7	1.5	11.3	1.5	10.6	

switching characteristics over recommended operating free-air temperature range,  
 $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$  (unless otherwise noted) (see Figure 1)

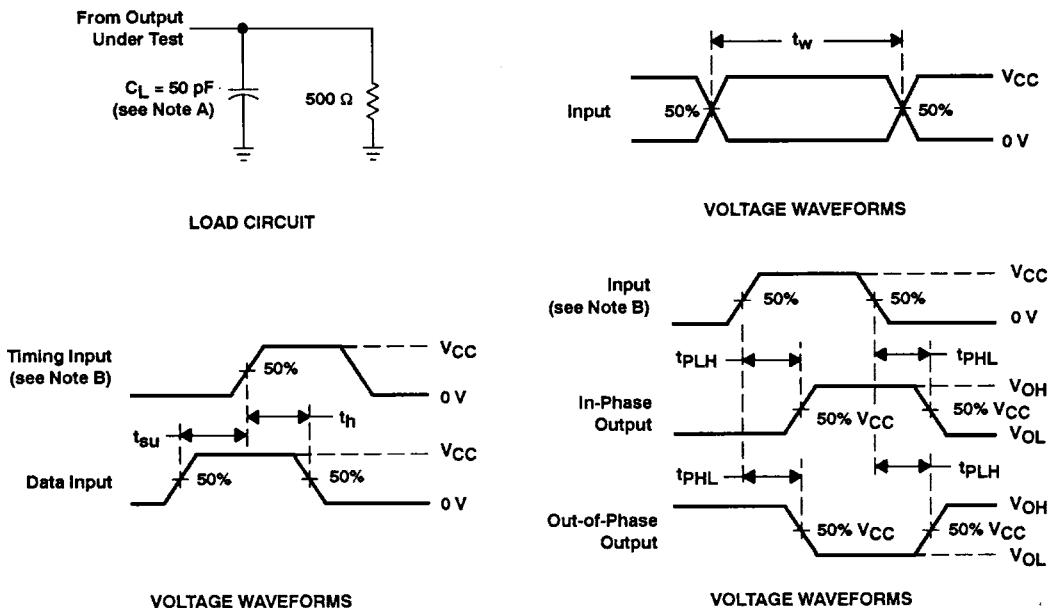
PARAMETER	FROM (INPUT)	TO (OUTPUT)	TA = 25°C			54AC11074		74AC11074		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			125	150		125		125		
t <sub>PLH</sub>	PRE or CLR	Q or $\bar{Q}$	1.5	4.2	6.6	1.5	7.5	1.5	7.1	ns
t <sub>PHL</sub>			1.5	4.7	8.2	1.5	9.6	1.5	9	
t <sub>PLH</sub>	CLK	Q or $\bar{Q}$	1.5	5.4	7.5	1.5	8.7	1.5	8.2	ns
t <sub>PHL</sub>			1.5	5	6.9	1.5	8	1.5	7.5	

operating characteristics,  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS			TYP	UNIT
	C <sub>pd</sub>	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}$ , $f = 1 \text{ MHz}$		
				30	pF

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**PARAMETER MEASUREMENT INFORMATION**



NOTES: A.  $C_L$  includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .

C. The outputs are measured one at a time with one input transition per measurement.

**Figure 1. Load Circuit and Voltage Waveforms**

